



## New Trends on Machine Learning Based Pattern Recognition and Classification

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### Message from the Guest Editors

Recently, because of the rapid development of computer hardware (e.g., GPU), the machine learning (ML) technique has been used in many areas, including image classification and segmentation, object detection and recognition, etc. All of them can be regarded as one branch of computer vision and can also be extended to artificial intelligence (AI) tasks.

In this Special Issue, we are expecting articles presenting new ideas, algorithms, and experimental results in the new trends on ML-based pattern recognition and classification. Topics of interest include, but are not limited to:

- Image classification, recognition, and segmentation;
- Object detection and tracking;
- Human age estimation and age synthesis;
- Image compression and video coding;
- Multimedia retrieval;
- Facial expression recognition and synthesis;
- ML-based remote-sensing image related applications;
- ML-based autonomous driving related applications;
- ML-based agriculture related applications;
- ML-based fashion related applications (e.g., virtual clothes try-on);
- ML-based AR, VR related applications;
- ML-based information security related applications.





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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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